

Applied Optics

A monthly publication of the
Optical Society of America

John N. Howard Editor

P. R. Wakeling Editorial Consultant

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Author	2487

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Published monthly for the Optical Society of America by the American Institute of Physics, at 20th and Northampton Streets, Easton, Pa. 18042. Office of the Editor: AFCRL, Bedford, Mass. 01730; 617-CR 4-6100. Office of the Editorial Consultant: WINC., 1500 Massachusetts Avenue N.W., Washington, D.C. 20005; 202-659-8054. Advertising office: American Institute of Physics, 335 E. 45th Street, New York, N.Y. 10017; 212-MU 5-1940. Subscription rates per year: \$10.00 to OSA members; non-members and libraries \$15.00. Single copies \$3.00; complete volumes \$30.00. Second class postage paid at Easton, Pa. © Copyright 1968 by the Optical Society of America, Inc.

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2. Principal subjects are given in boldface type. Cross-referenced subjects that should be consulted for more thorough coverage are given in lightface type after the principal subject.
3. (L), (MR), (N), (B), (P) indicate: (L) Letter to the Editor; (MR) meeting report; (N) from notes in one of the departments and not in a regular article; (B) book or book review; (P) patent. (E), (T), (E/T), (T/E) indicate the article is experimental, theoretical, or both; (R) indicates a review article.

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